

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(measur\$4 with thickness) and ((compar\$3 or analyze) with first with second).clm. and (wafer or semiconductor)	EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/17 14:38
L2	2	((("6045433") or ("5393624")).PN.	US-PGPUB; USPAT	OR	OFF	2005/10/17 14:38
L3	75	("3707760" "4121936" "4285433" "4500615" "4738910" "4778326" "4841156" "4851311" "4977330" "5220405").PN. OR ("5393624").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/17 14:39
S1	5	punnoose.xa. and finarov.in.	US-PGPUB; USPAT	OR	ON	2005/10/16 19:02
S2	5	S1 and thickness	US-PGPUB; USPAT	OR	ON	2005/10/16 17:38
S3	5	S2 and (control\$4 with process\$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 16:59
S4	5	S3 and layer\$1	US-PGPUB; USPAT	OR	ON	2005/10/16 18:49
S5	0	S4 and quality.clm.	US-PGPUB; USPAT	OR	ON	2005/10/16 17:01
S6	3	S4 and quality	US-PGPUB; USPAT	OR	ON	2005/10/16 17:54
S7	1428	kla adj tencor	US-PGPUB; USPAT	OR	ON	2005/10/16 17:12
S8	22	S7 and 356/630.ccls.	US-PGPUB; USPAT	OR	ON	2005/10/16 18:46
S9	334	356/630.ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S10	34	S9 and (galler\$3 or librar\$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S11	22	S10 and (second with measur\$5)	US-PGPUB; USPAT	OR	ON	2005/10/16 17:25
S12	20	S11 and (interpret\$3 or compar\$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S13	16	S11 and (interpret\$3 or compar\$3).clm.	US-PGPUB; USPAT	OR	ON	2005/10/16 17:26
S14	0	(interpret\$3 or compar\$3) adj ((first with measured) adj3 "with")	US-PGPUB; USPAT	OR	ON	2005/10/16 17:36
S15	9	(interpret\$3 or compar\$3) adj (first with measured)	US-PGPUB; USPAT	OR	ON	2005/10/16 17:37
S16	4	S15 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 17:36

S17	17	"356"/\$.ccls. and (layer and thickness and (galler\$3 or librar\$3) and (interpret\$3 or compar\$3)). clm.	US-PGPUB; USPAT	OR	ON	2005/10/16 17:39
S18	11	S17 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 17:51
S19	4	("5751427" "5963329" "6268916" "6657736").PN. OR ("6900892").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/16 17:51
S20	4	S19 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 17:51
S21	936	356/630,625,628,635,388237.1.ccls.	US-PGPUB; USPAT	OR	ON	2005/10/17 10:33
S22	715	S21 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 10:33
S23	59	S22 and (galler\$3 or librar\$3)	US-PGPUB; USPAT	OR	ON	2005/10/17 10:34
S24	54	S23 and (interpret\$3 or compar\$3)	US-PGPUB; USPAT	OR	ON	2005/10/16 18:48
S25	42	S24 and layer\$1 and thickness	US-PGPUB; USPAT	OR	ON	2005/10/17 10:34
S26	4	("5751427" "5963329" "6268916" "6657736").PN. OR ("6900892").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/16 18:54
S27	4	S26 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 18:54
S28	334	356/630.ccls. and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 18:57
S29	6	finarov.in. and (galler\$3 or librar\$3) and layer\$1 and thickness and process	US-PGPUB; USPAT	OR	ON	2005/10/16 19:03
S30	5	S29 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/16 19:04
S31	4	("5604344" "6113733").PN. OR ("6643017").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/17 09:59
S32	3	S31 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 10:04
S33	2	((analyzing adj second) with (based with first)) and (semiconductor or wafer)) and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 10:06
S34	1907	356/630,625,628,635,388,237.1.ccls.	US-PGPUB; USPAT	OR	ON	2005/10/17 10:33
S35	1465	S34 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 11:34

S36	73	S35 and (galler\$3 or librar\$3)	US-PGPUB; USPAT	OR	ON	2005/10/17 10:34
S37	52	S36 and layer\$1 and thickness	US-PGPUB; USPAT	OR	ON	2005/10/17 10:53
S38	29	S36 and etching and (measur\$4 with thickness)	US-PGPUB; USPAT	OR	ON	2005/10/17 11:19
S39	49	((first adj measur\$4) same (second adj measur\$4) same compar\$3) and (measur\$4 with thickness)	US-PGPUB; USPAT	OR	ON	2005/10/17 11:20
S40	30	S39 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 11:28
S41	67	(surface adj profile\$3) and (measur\$4 with thickness) and ((compar\$3 or analyze) with first with second) and (wafer or semiconductor)	US-PGPUB; USPAT	OR	ON	2005/10/17 12:12
S42	46	S41 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 13:05
S43	3	((("5,609,718") or ("5,655,951") or ("5,801,066")).PN.	US-PGPUB; USPAT	OR	OFF	2005/10/17 11:40
S44	388	(measur\$4 with thickness) and ((compar\$3 or analyze) with first with second).clm. and (wafer or semiconductor)	US-PGPUB; USPAT	OR	ON	2005/10/17 14:34
S45	260	S44 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 12:16
S46	26	("5081796" "5413941" "5433651" "5605760" "5640242" "5672091" "5791969" "5838447" "5872633" "5893796" "5899792" "5949927" "5964643" "6159073").PN. OR ("6296548").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/10/17 13:05
S47	24	S46 and @ad<="20020626"	US-PGPUB; USPAT	OR	ON	2005/10/17 13:05